



填充率  $r/a = 0.45$ , 介电常数取自文献[7]. 图 2(a) 和(b)是平面波在 InP 薄膜正方网格结构中沿  $\Gamma$ -X 入射( $z$  方向)时不同周期层 TE, TM 偏振模式的光子能带透射曲线. 可以看出, 两种偏振模式在可见光和近红外波段均有一个光子带隙存在, 随着周期层

数的增加, 两种偏振模式透射率逐渐减小. 周期层为 8 层时, TE, TM 两种偏振模式在  $530 \sim 700\text{nm}$  和  $800 \sim 940\text{nm}$  两个波长范围内有重叠的光子带隙存在.

图 3 给出了电磁波在 InP 薄膜正方网格二维光

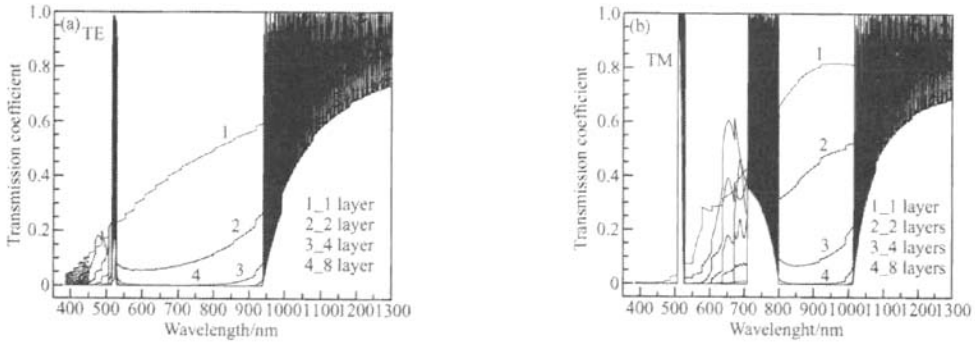


图 2 InP 薄膜网格二维光子晶体沿  $z$  方向不同层数的计算透射谱 (a) TE 模式; (b) TM 模式

Fig. 2 Theoretical transmission versus photon energy for TE (a) and for TM (b) of InP based network

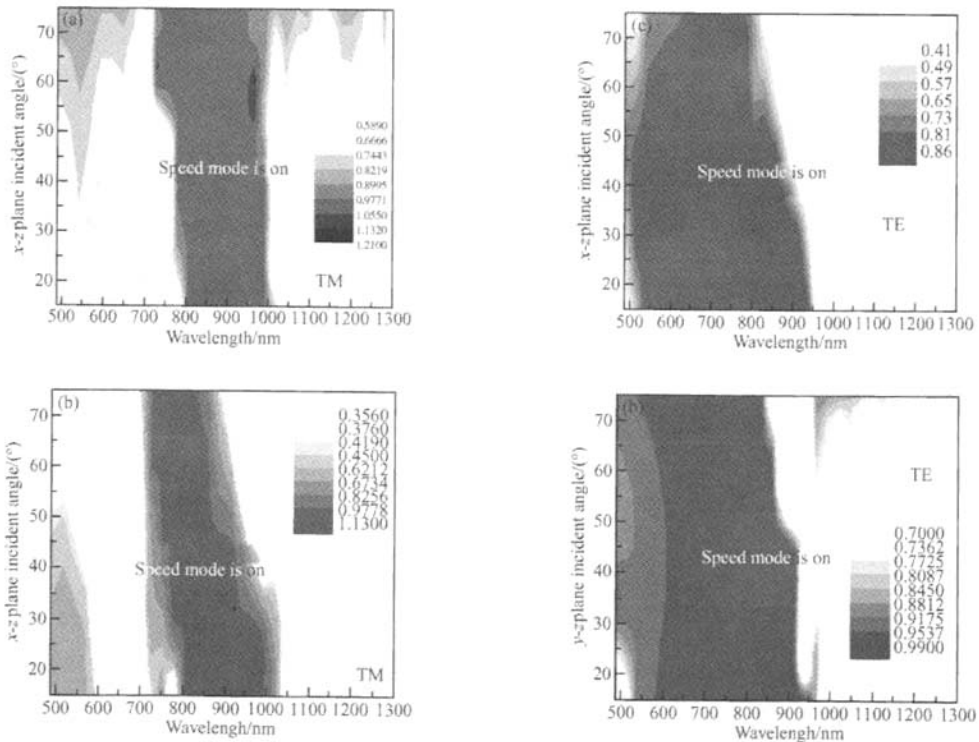


图 3 电磁波沿  $z$  方向入射后, 在  $x$ - $z$  (和  $y$ - $z$ ) 平面内由  $z$  方向向  $x$  轴 (和  $y$  轴) 偏转时, 不同掠射角对应不同波长的透射谱 对 TM 模式(a)  $x$ - $z$  平面内偏转, (b)  $y$ - $z$  平面内偏转; 对 TE 模式(c)  $x$ - $z$  平面内偏转, (d)  $y$ - $z$  平面内偏转

Fig. 3 Calculated in and out of plane angular response for InP based network, in which the zero angle of incidence corresponds to an incidence along the  $z'$  direction. Results for TM are shown in (a) for an angular scan within the periodic  $x$ - $z$  plane and (b) the  $y$ - $z$  plane. Results for TE are shown in (c) for an angular scans within the periodic  $x$ - $z$  plane and (d) the  $y$ - $z$  plane.

子晶体内沿着  $\Gamma$ -X 方向 ( $z$  轴) 入射后, 在  $x$ - $z$  (和  $y$ - $z$ ) 平面内由  $\Gamma$ -X 方向向  $x$  轴 (和  $y$  轴) 偏转时, 不同掠射角所对应不同波长的 TM, TE 两种偏振模式的透射率曲线. 图中曲线周期层共 8 层, InP 薄膜正方形网格二维光子晶体晶格常数为 250nm, 填充比为 0.45. 从图中可看出, 随掠射角增加带隙位置和宽度的变化情况. 随掠射角的增加 TE, TM 两种模式带隙都有向较高光子能量波段移动的趋势. 对于 TE 模式, 如图(c)所示, 在  $x$ - $z$  平面内随掠射角的增加带隙有变窄的趋势. 在  $y$ - $z$  平面内随掠射角增加带隙宽度不变, 当掠射角超过  $70^\circ$  时, 有较窄带隙产生, 如图(d)所示. 对于 TM 模式, 如图(a), 在  $x$ - $z$  平面内随掠射角的增加带隙稍有变宽. 当掠射角大于  $60^\circ$  时, 有较窄带隙产生. 在  $y$ - $z$  平面内随掠射角增加带隙变窄, 当掠射角达到  $50^\circ$  时, 低能量波段有一较窄带隙逐渐消失, 如图(b)所示.

#### 4 结论

使用转移矩阵方法从理论上计算了 InP 薄膜正方形网格的光子带隙结构及分布. 结果表明, InP 薄膜正方形网格二维光子晶体, 在可见光和近红外波段

TE, TM 两种偏振模式均有带隙存在, 且 TE, TM 两种模式带隙在 530~700nm 和 800~940nm 两个波段完全重叠. 带隙宽度和位置随掠射角变化较小, 透射率接近于零. 属于不完全带隙光子晶体.

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## Band Gaps of Two-Dimensional Photonic Crystal Structure Using InP Films\*

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**Abstract:** The concept and method of analysis of photonic crystals and band gaps are introduced into InP -film network structure, which is treated theoretically as photonic crystals. We investigate different aspects of the absolute photonic band gap (PBG) formation for 2D photonic crystal (PC) consisting of air bars drilled into InP films. The formation of PBG is exhibited and confirmed by a calculation of the transfer matrix method (TMM). We find that for InP based networks for a lattice constant of  $0.45a$  ( $a = 250\text{nm}$ ) two PBGs exist, which ranges are from 530 to 700nm and from 800 to 940nm at visible and near-infrared frequency.

**Key words:** InP films; TMM method; photonic crystals

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